

MOS FIELD EFFECT TRANSISTOR μ PA2794GR

SWITCHING N- AND P-CHANNEL POWER MOS FET

DESCRIPTION

The μ PA2794GR is N- and P-channel MOS Field Effect Transistors designed for Motor Drive application.

FEATURES

• Low on-state resistance

N-channel RDS(on)1 = 25 m Ω MAX. (VGS = 10 V, ID = 2.8 A)

 $R_{DS(on)2} = 33 \text{ m}\Omega \text{ MAX.} \text{ (V}_{GS} = 4.5 \text{ V}, I_D = 2.8 \text{ A)}$

P-channel R_{DS(on)1} = 43 m Ω MAX. (V_{GS} = -10 V, I_D = -2.8 A)

 $R_{DS(on)2} = 54 \text{ m}\Omega \text{ MAX}. \text{ (Vgs = -4.5 V, ID = -2.8 A)}$

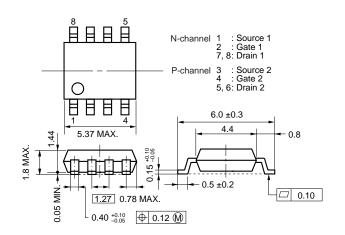
• Low input capacitance

N-channel Ciss = 2200 pF TYP.

P-channel Ciss = 2200 pF TYP.

- · Built-in gate protection diode
- Small and surface mount package (Power SOP8)

PACKAGE DRAWING (Unit: mm)

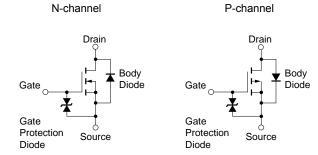


ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE	
μPA2794GR-E1-AZ Note				
μPA2794GR-E2-AZ ^{Note}	Sn-Bi	Tape 2500 p/reel	Power SOP8	

Note Pb-free (This product does not contain Pb in external electrode).

EQUIVALENT CIRCUITS



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD.

When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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Document No. G18594EJ1V0DS00 (1st edition) Date Published January 2007 NS CP(K) Printed in Japan

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ABSOLUTE MAXIMUM RATINGS (TA = 25°C. All terminals are connected.)

PARAMETER	SYMBOL	N-CHANNEL	P-CHANNEL	UNIT
Drain to Source Voltage (V _{GS} = 0 V)	VDSS	V _{DSS} 60		V
Gate to Source Voltage (V _{DS} = 0 V)	Vgss	±20	∓20	V
Drain Current (DC)	ent (DC) I _{D(DC)} ±5.5		∓5.5	Α
Drain Current (pulse) Note1	I _{D(pulse)}	±22	∓22	А
Total Power Dissipation (1 unit) Note2	P _{T1}	1.7		W
Total Power Dissipation (2 units) Note2	P _{T2}	2.0		W
Channel Temperature	Tch	150		°C
Storage Temperature	Tstg	−55 to +150		°C
Single Avalanche Current Note3	las	5.5	-5.5	А
Single Avalanche Energy Note3	Eas	3.03		mJ

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

- 2. Mounted on ceramic substrate of 2000 $\mathrm{mm}^2\,\mathrm{x}$ 1.6 mm
- 3. Starting Tch = 25°C, Vdd = 30 V, Rg = 25 Ω , L = 100 μ H, Vgs = 20 \rightarrow 0 V

ELECTRICAL CHARACTERISTICS (TA = 25°C. All terminals are connected.)

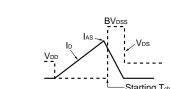
N-channel

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 60 V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μΑ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance Note	y _{fs}	V _{DS} = 10 V, I _D = 2.8 A	4	7.6		S
Drain to Source On-state Resistance Note	R _{DS(on)1}	V _{GS} = 10 V, I _D = 2.8 A		19.5	25	mΩ
	R _{DS(on)2}	V _{GS} = 4.5 V, I _D = 2.8 A		23	33	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V,		2200		pF
Output Capacitance	Coss	V _{GS} = 0 V,		245		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		136		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 30 V, I _D = 2.8 A,		10		ns
Rise Time	tr	V _{GS} = 10 V,		16		ns
Turn-off Delay Time	t _{d(off)}	R _G = 0 Ω		58		ns
Fall Time	tf			7.5		ns
Total Gate Charge	Q _G	I _D = 5.5 A,		41		nC
Gate to Source Charge	Q _{GS}	V _{DD} = 48 V,		6.3		nC
Gate to Drain Charge	Q _{GD}	V _{GS} = 10 V		11		nC
Body Diode Forward Voltage Note	V _{F(S-D)}	I _F = 5.5 A, V _{GS} = 0 V		0.8	1.5	V
Reverse Recovery Time	trr	I _F = 5.5 A, V _{GS} = 0 V,		28		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		29		nC

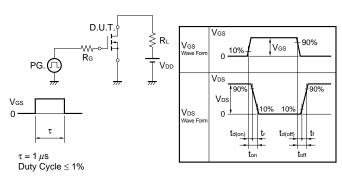
Note Pulsed

TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c|c} \text{D.U.T} \\ \text{RG} = 25 \ \Omega \\ \text{Vos} = 20 \rightarrow 0 \ \text{V} \end{array}$



TEST CIRCUIT 2 SWITCHING TIME



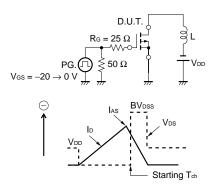
TEST CIRCUIT 3 GATE CHARGE

P-channel

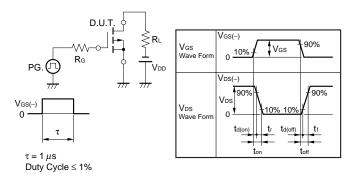
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = -60 V, V _{GS} = 0 V			-10	μΑ
Gate Leakage Current	Igss	V _{GS} = ∓20 V, V _{DS} = 0 V			∓10	μΑ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = -10 V, I _D = -1 mA	-1.0	-1.7	-2.5	V
Forward Transfer Admittance Note	yfs	V _{DS} = -10 V, I _D = -2.8 A	5	10		S
Drain to Source On-state Resistance Note	R _{DS(on)1}	V _{GS} = -10 V, I _D = -2.8 A		33	43	mΩ
	R _{DS(on)2}	V _{GS} = -4.5 V, I _D = -2.8 A		36	54	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V,		2200		pF
Output Capacitance	Coss	V _{GS} = 0 V,		270		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		200		pF
Turn-on Delay Time	t _{d(on)}	$V_{DD} = -30 \text{ V}, I_{D} = -2.8 \text{ A},$		10		ns
Rise Time	tr	V _{GS} = -10 V,		22		ns
Turn-off Delay Time	t _{d(off)}	R _G = 0 Ω		150		ns
Fall Time	tf			23		ns
Total Gate Charge	Q _G	I _D = -5.5 A,		45		nC
Gate to Source Charge	Qgs	V _{DD} = -48 V,		4.3		nC
Gate to Drain Charge	Q _{GD}	V _{GS} = -10 V		13		nC
Body Diode Forward Voltage Note	V _{F(S-D)}	I _F = 5.5 A, V _{GS} = 0 V		0.83	1.5	V
Reverse Recovery Time	trr	I _F = -5.5 A, V _{GS} = 0 V,		46		ns
Reverse Recovery Charge	Qrr	di/dt = −50 A/ <i>µ</i> s		29		nC

Note Pulsed

TEST CIRCUIT 1 AVALANCHE CAPABILITY



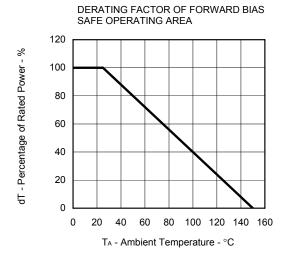
TEST CIRCUIT 2 SWITCHING TIME



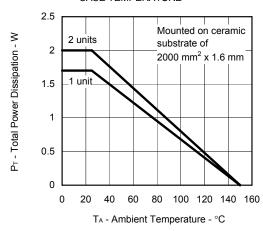
TEST CIRCUIT 3 GATE CHARGE

TYPICAL CHARACTERISTICS (TA = 25°C)

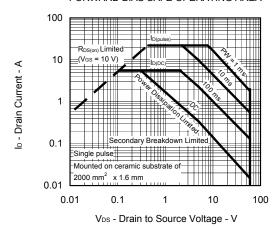
(1) N-channel



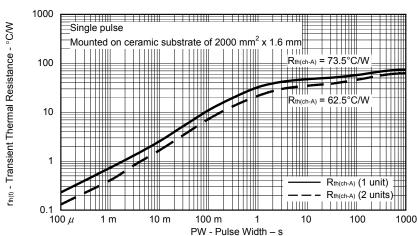
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



FORWARD BIAS SAFE OPERATING AREA



TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

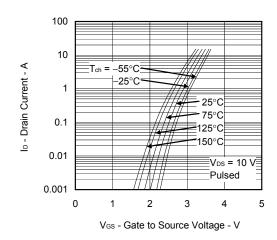


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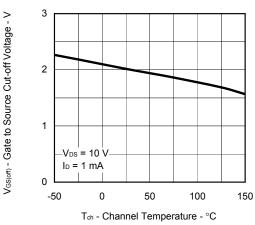
DRAIN TO SOURCE VOLTAGE 50 40 10 V Ip - Drain Current - A 30 $V_{GS} = 4.5$ 20 10 Pulsed 0 0 0.5 1 1.5 2 V_{DS} - Drain to Source Voltage - V

DRAIN CURRENT vs.

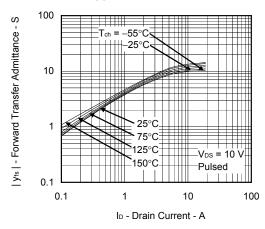




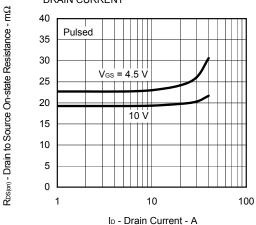
GATE TO SOURCE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



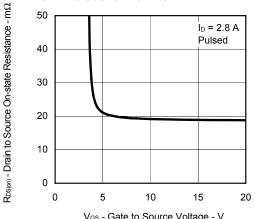
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



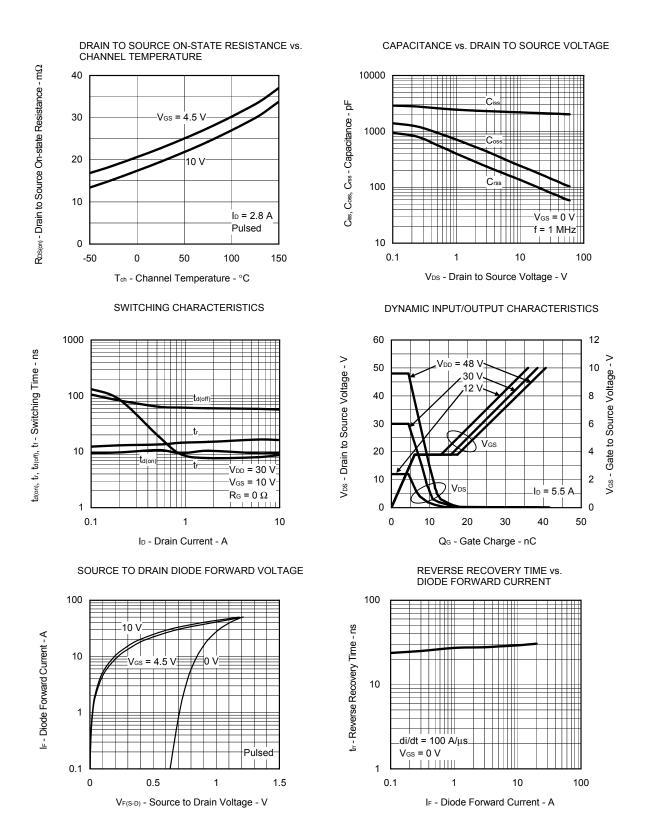
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

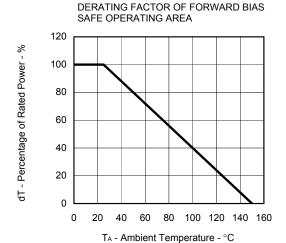


V_{GS} - Gate to Source Voltage - V

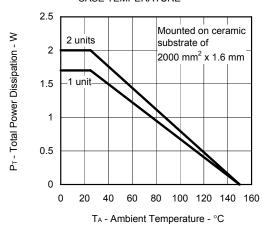


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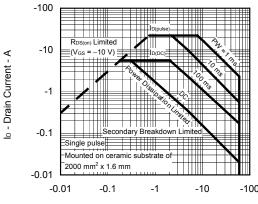
(2) P-channel

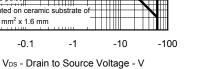


TOTAL POWER DISSIPATION vs. CASE TEMPERATURE

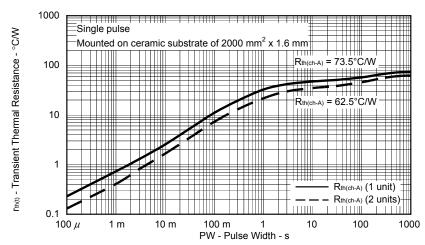


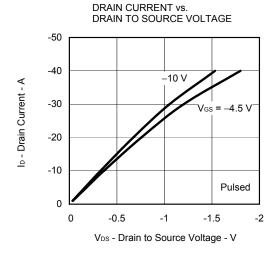
FORWARD BIAS SAFE OPERATING AREA

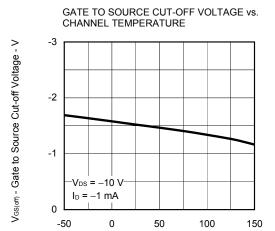




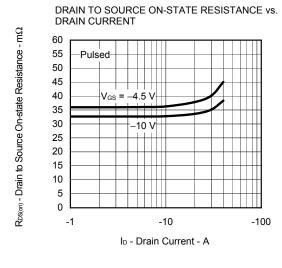
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

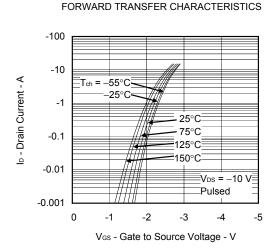


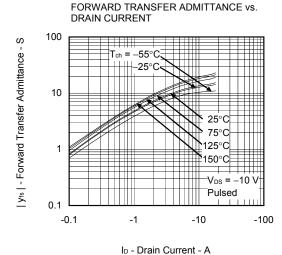


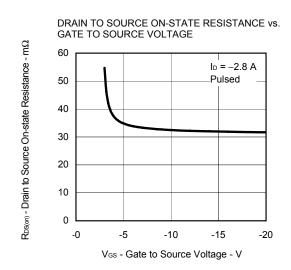


Tch - Channel Temperature - °C



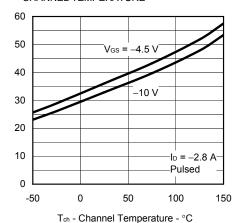






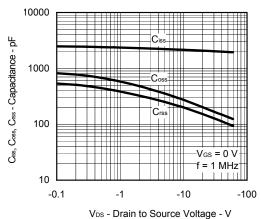
NEC μ PA2794GR

DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE

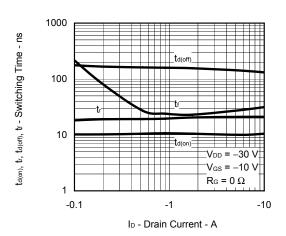


R_{DS(m)} - Drain to Source On-state Resistance - mΩ

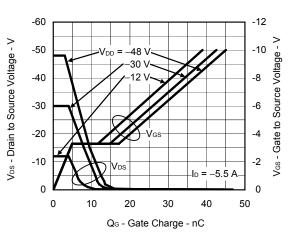
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



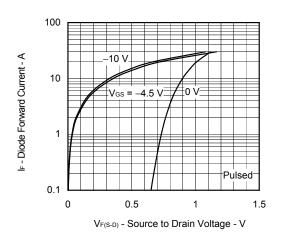
SWITCHING CHARACTERISTICS



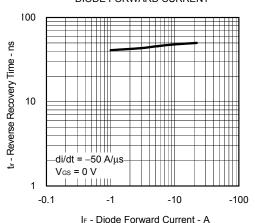
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE

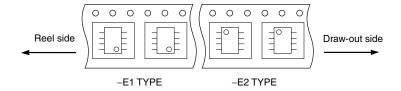


REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT

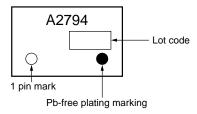


TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



MARKING INFORMATION



RECOMMENDED SOLDERING CONDITIONS

The μ PA2794GR should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below	IR60-00-3
	Time at maximum temperature: 10 seconds or less	
	Time of temperature higher than 220°C: 60 seconds or less	
	Preheating time at 160 to 180°C: 60 to 120 seconds	
	Maximum number of reflow processes: 3 times	
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less	
Partial heating	Maximum temperature (Pin temperature): 350°C or below	P350
	Time (per side of the device): 3 seconds or less	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less	

Caution Do not use different soldering methods together (except for partial heating).

NEC μ PA2794GR

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